



FQD12P10 / FQU12P10

100V P-Channel MOSFET

General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

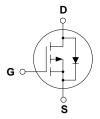
Features

- -9.4A, -100V, $R_{DS(on)} = 0.29\Omega$ @ $V_{GS} = -10 \text{ V}$
- Low gate charge (typical 21 nC)
- Low Crss (typical 65 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD12P10 / FQU12P10	Units
V _{DSS}	Drain-Source Voltage		-100	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		-9.4	А
			-6.0	А
I _{DM}	Drain Current - Pulsed	(Note 1)	-37.6	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	370	mJ
I _{AR}	Avalanche Current	(Note 1)	-9.4	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-6.0	V/ns
P _D	P _D Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.5	°C/W
R _{θJA} Thermal Resistance, Junction-to-Ambient *			50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

 * When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-100			V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = -250 μA, Referenced to 25°0		-0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -100 V, V _{GS} = 0 V			-1	μΑ
		V _{DS} = -80 V, T _C = 125°C			-10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	racteristics		<u>'</u>			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -4.7 A		0.24	0.29	Ω
9 _{FS}	Forward Transconductance	V _{DS} = -40 V, I _D = -4.7 A (Note 4)	6.3		S
C _{iss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		220	290	pF pF
C _{rss}	Reverse Transfer Capacitance			65	85	pF
Switchi	ing Characteristics	T				
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -50 \text{ V}, I_{D} = -11.5 \text{ A},$		15	40	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		160	330	ns
t _{d(off)}	Turn-Off Delay Time	()		35	80	ns
t _f	Turn-Off Fall Time	(Note 4, 5	o)	60	130	ns
Q_g	Total Gate Charge	$V_{DS} = -80 \text{ V}, I_{D} = -11.5 \text{ A},$		21	27	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V		4.6		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5	5)	11.5		nC
	Source Diode Characteristics at Maximum Continuous Drain-Source Dio				-9.4	А
I _{SM}	Maximum Pulsed Drain-Source Diode F	orward Current			-37.6	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -9.4 \text{ A}$			-4.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = -11.5 \text{ A,}$		110		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.47		μС

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 6.3mH, I $_{AS}$ = -9.4A, V $_{DD}$ = -25V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C 3. I $_{SD}$ ≤ -11.5A, di/dt ≤ 300A/ μ s, V $_{DD}$ ≤ BV $_{DSS}$, Starting T $_{J}$ = 25°C 4. Pulse Test : Pulse width ≤ 300 μ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

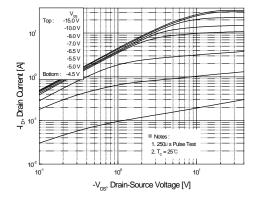


Figure 1. On-Region Characteristics

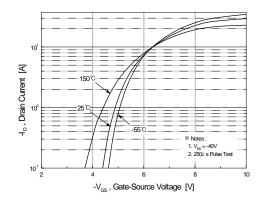


Figure 2. Transfer Characteristics

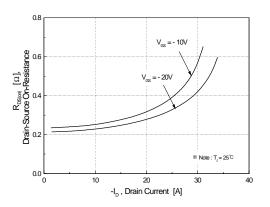


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

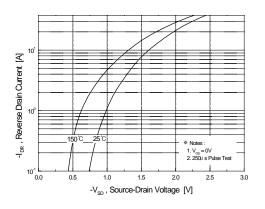


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

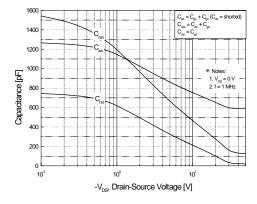


Figure 5. Capacitance Characteristics

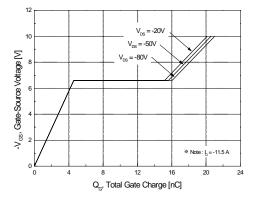


Figure 6. Gate Charge Characteristics

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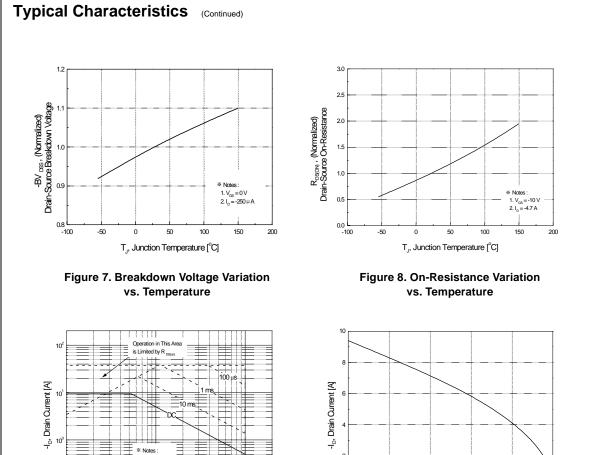


Figure 9. Maximum Safe Operating Area

-V_{DS}, Drain-Source Voltage [V]

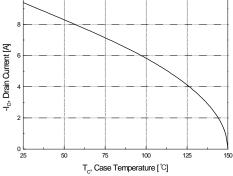


Figure 10. Maximum Drain Current vs. Case Temperature

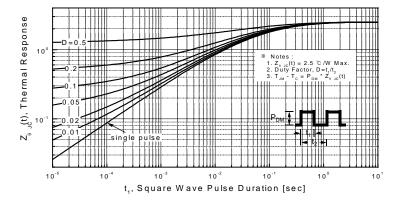
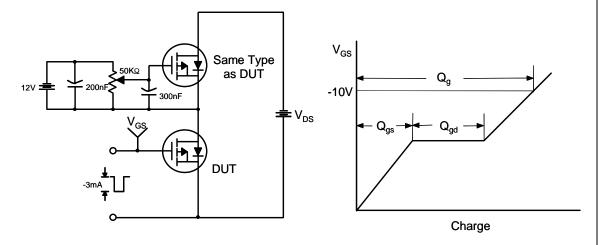


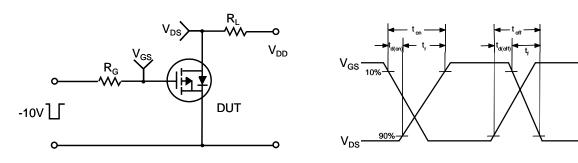
Figure 11. Transient Thermal Response Curve

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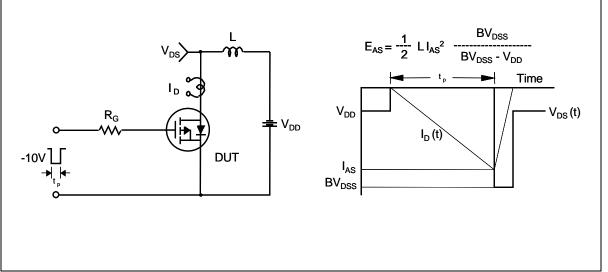




Resistive Switching Test Circuit & Waveforms

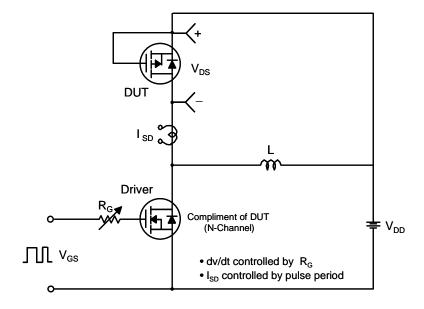


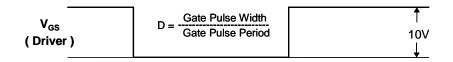
Unclamped Inductive Switching Test Circuit & Waveforms



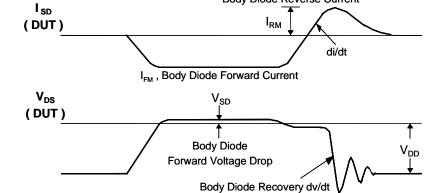
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Peak Diode Recovery dv/dt Test Circuit & Waveforms





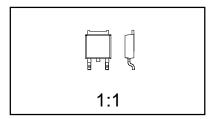
Body Diode Reverse Current





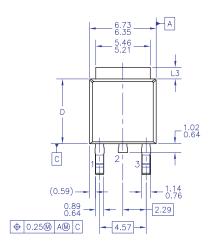
TO-252 (DPAK) (FS PKG Code 36)



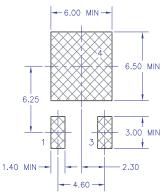


Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

Part Weight per unit (gram): 0.33

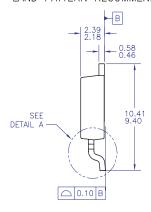


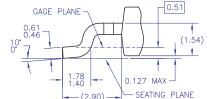
SEE NOTE D



LAND PATTERN RECOMMENDATION







- NOTES: UNLESS OTHERWISE SPECIFIED

 A) ALL DIMENSIONS ARE IN MILLIMETERS.

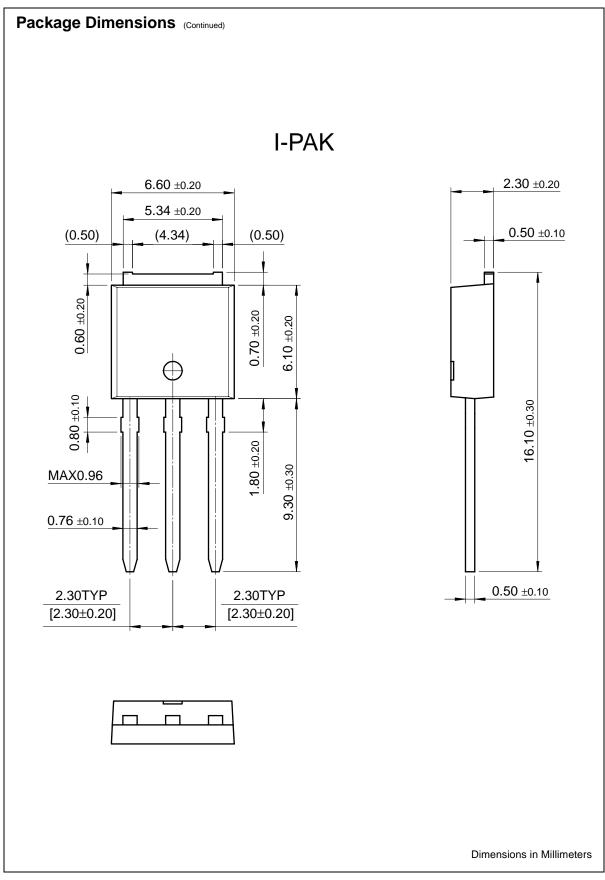
 B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

 C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

 - HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.

 DIMENSIONS L3,D,E1&D1 TABLE:

 		,
	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D.1	5.21 MIN	4.57 MIN







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